

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
		"PLL" or ("phase locked loops")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2003/03/19 13:35
S1	967	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 12:30
S2	281	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2003/03/19 14:54
S3	365	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ti. ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/03/19 15:05
S4	300	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/03/19 15:07
S5	163	((((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register")))) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/03/21 10:40

S6	2	"5235600".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/03/21 10:45
S7	12133	(memor\$3 near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/06/29 14:18
S8	12133	(memor\$3 near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/29 14:18
S9	23	(memor\$3 near test\$3) and (BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/29 14:28
S10	28	(BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/29 14:28
S11	5	((BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator")) not ((memor\$3 near test\$3) and (BIST "self test" "built-in self-test" "in-circuit test") and ("ALPG" "programmable algorithmic pattern generator"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/29 14:28
S12	8	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) with ("programmable algorithmic pattern generator" "ALPG")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 12:31
S13	10	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) same ("programmable algorithmic pattern generator" "ALPG")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 12:31
S14	26	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) and ("programmable algorithmic pattern generator" "ALPG")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 13:52

S15	12	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 13:53
S16	12	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")) not ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and ("programmable algorithmic pattern generator" "ALPG"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 13:53
S17	12	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")) not ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) same ("programmable algorithmic pattern generator" "ALPG"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 13:53
S18	12	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) and (programmable near "pattern generator")) not ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with ("programmable algorithmic pattern generator" "ALPG"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/01 13:53
S19	57549	"PLL" or ("phase locked loops")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/03/19 13:47